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01 SEP 2005
PATENT
450100-05491

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sakae OKAZAKI

International Application No.: PCT/JP05/001393

International Filing Date: February 1, 2005

For: AUTOMATIC FOCUS CONTROL APPARATUS AND
METHOD, RECORDING MEDIUM AND PROGRAM

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Sir:

Enclosed are copies of the publications, which were cited in the International Search
Report of International Application No. PCT/JP05/001393. Also enclosed is a copy of Form
PTO-1449 and the International Search Report.

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REMARKS

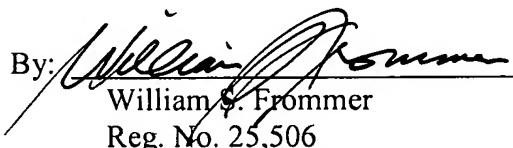
Entry of this Information Disclosure Statement and an early examination on the merits
are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorneys for Applicant

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Enclosures

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Sheet 1 of 1

Based on Form PTO-1449 (3/90) LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 450100-05491	INTERNATIONAL SERIAL NO. PCT/JP05/001393
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6 184 932	02/06/01	Tanaka			
	AB	6 222 588	04/24/01	Yamazaki et al.			
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AG	7 170439	07/04/95	Japan			NO
	AH	7 154676	06/16/95	Japan			NO
	AI	5 107451	04/30/93	Japan			NO
	AJ	6 339059	12/06/94	Japan			NO
	AK	2000 333072	11/30/00	Japan			NO
	AL	2001 86389	03/30/01	Japan			NO
	AM	2001 4914	01/12/01	Japan			NO
	AN	2002 350716	12/04/02	Japan			NO
	AO	11 153748	06/08/99	Japan			NO
	AP	8 265619	10/11/96	Japan			NO
	AQ	60 32482	02/19/85	Japan			NO

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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